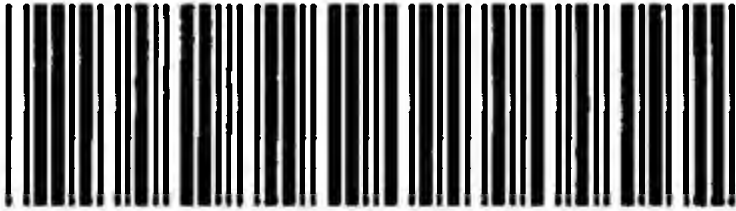


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,824	SHIUNG, DAVID	
	Examiner	Art Unit	
	Tan V. Mai	2193	

SEARCHED			
Class	Subclass	Date	Examiner
708	270-272	6/18/2007	MAI

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	6/18/2007	MAI